AMD Xilinx - XC3S200-5PQG208C Datasheet

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	480
Number of Logic Elements/Cells	4320
Total RAM Bits	221184
Number of I/O	141
Number of Gates	200000
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc3s200-5pqg208c

Table 3 shows the number of user I/Os as well as the number of differential I/O pairs available for each device/package combination.

Table 3: **Spartan-3 Device I/O Chart**

Available User I/Os and Differential (Diff) I/O Pairs by Package Type																				
Package	**VQ100 VQG100**		**CP132(1) CPG132**		**TQ144 TQG144**		**PQ208 PQG208**		**FT256 FTG256**		**FG320 FGG320**		**FG456 FGG456**		**FG676 FGG676**		**FG900 FGG900**		**FG1156(1) FGG1156**	
Footprint (mm)	16 x 16		8 x 8		22 x 22		30.6 x 30.6		17 x 17		19 x 19		23 x 23		27 x 27		31 x 31		35 x 35	
Device	**User**	**Diff**	**User**	**Diff**	**User**	**Diff**	**User**	**Diff**	**User**	**Diff**	**User**	**Diff**	**User**	**Diff**	**User**	**Diff**	**User**	**Diff**	**User**	**Diff**
XC3S50	63	29	89(1)	44(1)	97	46	124	56	–	–	–	–	–	–	–	–	–	–	–	–
XC3S200	63	29	–	–	97	46	141	62	173	76	–	–	–	–	–	–	–	–	–	–
XC3S400	–	–	–	–	97	46	141	62	173	76	221	100	264	116	–	–	–	–	–	–
XC3S1000	–	–	–	–	–	–	–	–	173	76	221	100	333	149	391	175	–	–	–	–
XC3S1500	–	–	–	–	–	–	–	–	–	–	221	100	333	149	487	221	–	–	–	–
XC3S2000	–	–	–	–	–	–	–	–	–	–	–	–	333	149	489	221	565	270	–	–
XC3S4000	–	–	–	–	–	–	–	–	–	–	–	–	–	–	489	221	633	300	712(1)	312(1)
XC3S5000	–	–	–	–	–	–	–	–	–	–	–	–	–	–	489	221	633	300	784(1)	344(1)

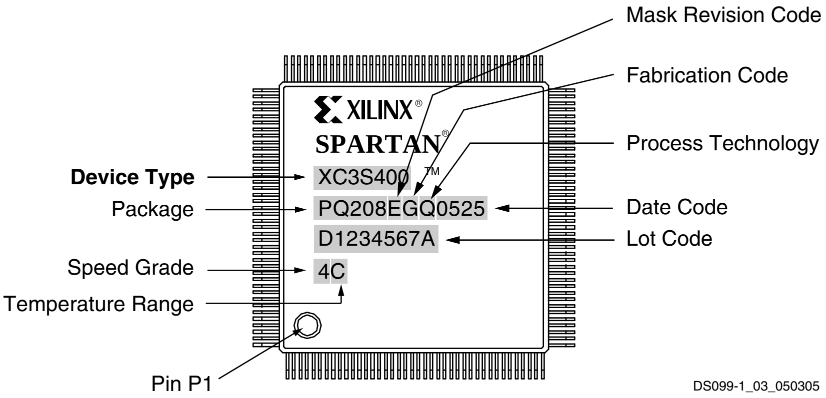
Notes:

1. The CP132, CPG132, FG1156, and FGG1156 packages are discontinued. See http://www.xilinx.com/support/documentation/spartan-3_customer_notices.htm.
2. All device options listed in a given package column are pin-compatible.
3. User = Single-ended user I/O pins. Diff = Differential I/O pairs.

Package Marking

Figure 2 shows the top marking for Spartan-3 FPGAs in the quad-flat packages. Figure 3 shows the top marking for Spartan-3 FPGAs in BGA packages except the 132-ball chip-scale package (CP132 and CPG132). The markings for the BGA packages are nearly identical to those for the quad-flat packages, except that the marking is rotated with respect to the ball A1 indicator. Figure 4 shows the top marking for Spartan-3 FPGAs in the CP132 and CPG132 packages.

The "`5C`" and "`4I`" part combinations may be dual marked as "`5C/4I`". Devices with the dual mark can be used as either -5C or -4I devices. Devices with a single mark are only guaranteed for the marked speed grade and temperature range. Some specifications vary according to mask revision. Mask revision E devices are errata-free. All shipments since 2006 have been mask revision E.



DS099-1_03_050305

Figure 2: **Spartan-3 FPGA QFP Package Marking Example for Part Number XC3S400-4PQ208C**

IOBs

For additional information, refer to the chapter entitled “Using I/O Resources” in UG331: *Spartan-3 Generation FPGA User Guide*.

IOB Overview

The Input/Output Block (IOB) provides a programmable, bidirectional interface between an I/O pin and the FPGA’s internal logic.

A simplified diagram of the IOB’s internal structure appears in Figure 7. There are three main signal paths within the IOB: the output path, input path, and 3-state path. Each path has its own pair of storage elements that can act as either registers or latches. For more information, see the Storage Element Functions section. The three main signal paths are as follows:

- The input path carries data from the pad, which is bonded to a package pin, through an optional programmable delay element directly to the I line. There are alternate routes through a pair of storage elements to the IQ1 and IQ2 lines. The IOB outputs I, IQ1, and IQ2 all lead to the FPGA’s internal logic. The delay element can be set to ensure a hold time of zero.
- The output path, starting with the O1 and O2 lines, carries data from the FPGA’s internal logic through a multiplexer and then a three-state driver to the IOB pad. In addition to this direct path, the multiplexer provides the option to insert a pair of storage elements.
- The 3-state path determines when the output driver is high impedance. The T1 and T2 lines carry data from the FPGA’s internal logic through a multiplexer to the output driver. In addition to this direct path, the multiplexer provides the option to insert a pair of storage elements. When the T1 or T2 lines are asserted High, the output driver is high-impedance (floating, hi-Z). The output driver is active-Low enabled.
- All signal paths entering the IOB, including those associated with the storage elements, have an inverter option. Any inverter placed on these paths is automatically absorbed into the IOB.

Storage Element Functions

There are three pairs of storage elements in each IOB, one pair for each of the three paths. It is possible to configure each of these storage elements as an edge-triggered D-type flip-flop (FD) or a level-sensitive latch (LD).

The storage-element-pair on either the Output path or the Three-State path can be used together with a special multiplexer to produce Double-Data-Rate (DDR) transmission. This is accomplished by taking data synchronized to the clock signal’s rising edge and converting them to bits synchronized on both the rising and the falling edge. The combination of two registers and a multiplexer is referred to as a Double-Data-Rate D-type flip-flop (FDDR). See Double-Data-Rate Transmission, page 12 for more information.

The signal paths associated with the storage element are described in Table 5.

Table 5: **Storage Element Signal Description**

Storage Element Signal	Description	Function
D	Data input	Data at this input is stored on the active edge of CK enabled by CE. For latch operation when the input is enabled, data passes directly to the output Q.
Q	Data output	The data on this output reflects the state of the storage element. For operation as a latch in transparent mode, Q will mirror the data at D.
CK	Clock input	A signal’s active edge on this input with CE asserted, loads data into the storage element.
CE	Clock Enable input	When asserted, this input enables CK. If not connected, CE defaults to the asserted state.
SR	Set/Reset	Forces storage element into the state specified by the SRHIGH/SRLOW attributes. The SYNC/ASYNC attribute setting determines if the SR input is synchronized to the clock or not.
REV	Reverse	Used together with SR. Forces storage element into the state opposite from what SR does.

Table 13: **Block RAM Port Signals *(Cont'd)***

Signal Description	Port A Signal Name	Port B Signal Name	Direction	Function
Data Output Bus	DOA	DOB	Output	Basic data access occurs whenever WE is inactive. The DO outputs mirror the data stored in the addressed memory location. Data access with WE asserted is also possible if one of the following two attributes is chosen: WRITE_FIRST and READ_FIRST. WRITE_FIRST simultaneously presents the new input data on the DO output port and writes the data to the address RAM location. READ_FIRST presents the previously stored RAM data on the DO output port while writing new data to RAM. A third attribute, NO_CHANGE, latches the DO outputs upon the assertion of WE. It is possible to configure a port's total data path width (w) to be 1, 2, 4, 9, 18, or 36 bits. This selection applies to both the DI and DO paths. See the DI signal description.
Parity Data Output(s)	DOPA	DOPB	Output	Parity inputs represent additional bits included in the data input path to support error detection. The number of parity bits "p" included in the DI (same as for the DO bus) depends on a port's total data path width (w). See Table 14.
Write Enable	WEA	WEB	Input	When asserted together with EN, this input enables the writing of data to the RAM. In this case, the data access attributes WRITE_FIRST, READ_FIRST or NO_CHANGE determines if and how data is updated on the DO outputs. See the DO signal description. When WE is inactive with EN asserted, read operations are still possible. In this case, a transparent latch passes data from the addressed memory location to the DO outputs.
Clock Enable	ENA	ENB	Input	When asserted, this input enables the CLK signal to synchronize Block RAM functions as follows: the writing of data to the DI inputs (when WE is also asserted), the updating of data at the DO outputs as well as the setting/resetting of the DO output latches. When de-asserted, the above functions are disabled.
Set/Reset	SSRA	SSRB	Input	When asserted, this pin forces the DO output latch to the value that the SRVAL attribute is set to. A Set/Reset operation on one port has no effect on the other ports functioning, nor does it disturb the memory's data contents. It is synchronized to the CLK signal.
Clock	CLKA	CLKB	Input	This input accepts the clock signal to which read and write operations are synchronized. All associated port inputs are required to meet setup times with respect to the clock signal's active edge. The data output bus responds after a clock-to-out delay referenced to the clock signal's active edge.

Port Aspect Ratios

On a given port, it is possible to select a number of different possible widths ($w - p$) for the DI/DO buses as shown in Table 14. These two buses always have the same width. This data bus width selection is independent for each port. If the data bus width of Port A differs from that of Port B, the Block RAM automatically performs a bus-matching function. When data are written to a port with a narrow bus, then read from a port with a wide bus, the latter port will effectively combine "narrow" words to form "wide" words. Similarly, when data are written into a port with a wide bus, then read from a port with a narrow bus, the latter port will divide "wide" words to form "narrow" words. When the data bus width is eight bits or greater, extra parity bits become available. The width of the total data path (w) is the sum of the DI/DO bus width and any parity bits (p).

The width selection made for the DI/DO bus determines the number of address lines according to the relationship expressed below:

$$r = 14 - [\log(w-p)/\log(2)] \qquad \textit{Equation 1}$$

In turn, the number of address lines delimits the total number (n) of addressable locations or depth according to the following equation:

$$n = 2^r \qquad \textit{Equation 2}$$

DFS Clock Output Connections

There are two basic cases that determine how to connect the DFS clock outputs: on-chip and off-chip, which are illustrated in sections [a] and [c], respectively, of Figure 21. This is similar to what has already been described for the DLL component. See DLL Clock Output and Feedback Connections, page 34.

In the on-chip case, it is possible to connect either of the DFS's two output clock signals through general routing resources to the FPGA's internal registers. Either a Global Clock Buffer (BUFG) or a BUFGMUX affords access to the global clock network. The optional feedback loop is formed in this way, routing CLK0 to a global clock net, which in turn drives the CLKFB input.

In the off-chip case, the DFS's two output clock signals, plus CLK0 for an optional feedback loop, can exit the FPGA using output buffers (OBUF) to drive a clock network plus registers on the board. The feedback loop is formed by feeding the CLK0 signal back into the FPGA using an IBUFG, which directly accesses the global clock network, or an IBUF. Then, the global clock net is connected directly to the CLKFB input.

Phase Shifter (PS)

The DCM provides two approaches to controlling the phase of a DCM clock output signal relative to the CLKIN signal: First, there are nine clock outputs that employ the DLL to achieve a desired phase relationship: CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, CLKDV CLKFX, and CLKFX180. These outputs afford “coarse” phase control.

The second approach uses the PS component described in this section to provide a still finer degree of control. The PS component is only available when the DLL is operating in its low-frequency mode. The PS component phase shifts the DCM output clocks by introducing a "fine phase shift" (T_{PS}) between the CLKFB and CLKIN signals inside the DLL component. The user can control this fine phase shift down to a resolution of 1/256 of a CLKIN cycle or one tap delay (DCM_TAP), whichever is greater. When in use, the PS component shifts the phase of all nine DCM clock output signals together. If the PS component is used together with a DCM clock output such as the CLK90, CLK180, CLK270, CLK2X180 and CLKFX180, then the fine phase shift of the former gets added to the coarse phase shift of the latter.

PS Component Enabling and Mode Selection

The CLKOUT_PHASE_SHIFT attribute enables the PS component for use in addition to selecting between two operating modes. As described in Table 20, this attribute has three possible values: NONE, FIXED and VARIABLE. When CLKOUT_PHASE_SHIFT is set to NONE, the PS component is disabled and its inputs, PSEN, PSCLK, and PSINCDEC, must be tied to GND. The set of waveforms in section [a] of Figure 22 shows the disabled case, where the DLL maintains a zero-phase alignment of signals CLKFB and CLKIN upon which the PS component has no effect. The PS component is enabled by setting the attribute to either the FIXED or VARIABLE values, which select the Fixed Phase mode and the Variable Phase mode, respectively. These two modes are described in the sections that follow

Determining the Fine Phase Shift

The user controls the phase shift of CLKFB relative to CLKIN by setting and/or adjusting the value of the PHASE_SHIFT attribute. This value must be an integer ranging from –255 to +255. The PS component uses this value to calculate the desired fine phase shift (T_{PS}) as a fraction of the CLKIN period (T_{CLKIN}). Given values for PHASE-SHIFT and T_{CLKIN}, it is possible to calculate T_{PS} as follows:

$$T_{PS} = T_{CLKIN}(\mathrm{PHASE\_SHIFT}/256) \qquad \textit{Equation 4}$$

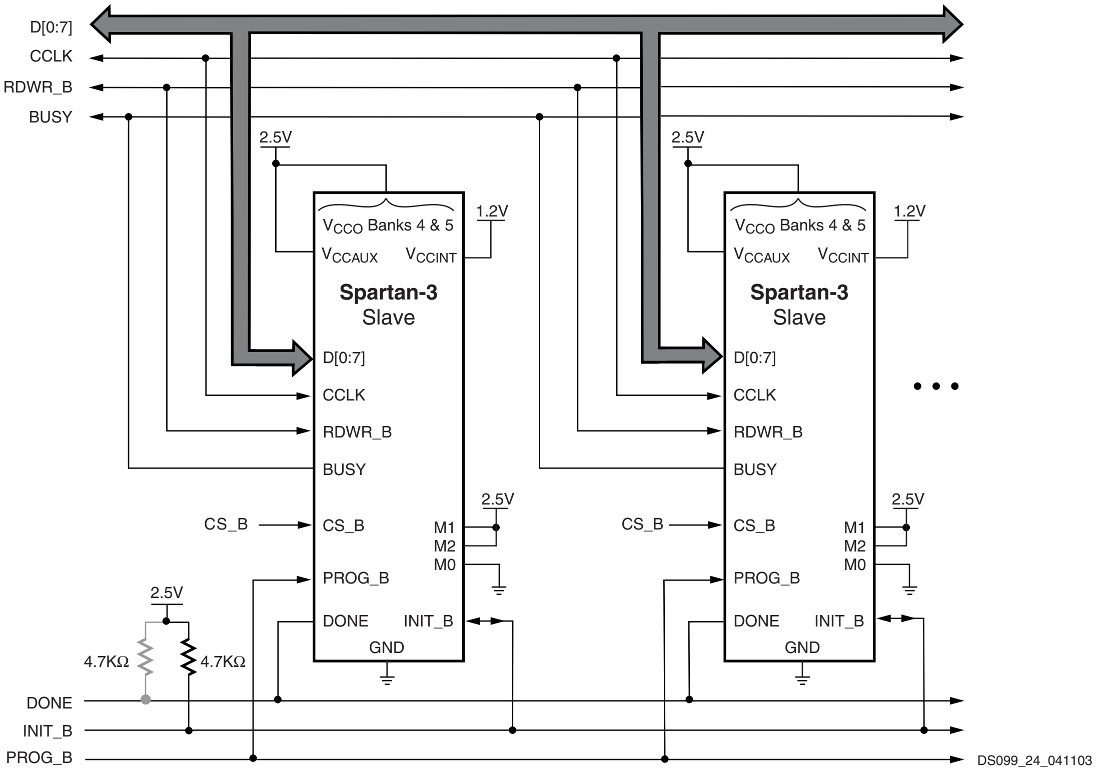
Both the Fixed Phase and Variable Phase operating modes employ this calculation. If the PHASE_SHIFT value is zero, then CLKFB and CLKIN will be in phase, the same as when the PS component is disabled. When the PHASE_SHIFT value is positive, the CLKFB signal will be shifted later in time with respect to CLKIN. If the attribute value is negative, the CLKFB signal will be shifted earlier in time with respect to CLKIN.

The Fixed Phase Mode

This mode fixes the desired fine phase shift to a fraction of the T_{CLKIN}, as determined by Equation 4 and its user-selected PHASE_SHIFT value P. The set of waveforms insection [b] of Figure 22 illustrates the relationship between CLKFB and CLKIN in the Fixed Phase mode. In the Fixed Phase mode, the PSEN, PSCLK and PSINCDEC inputs are not used and must be tied to GND. Fixed phase shift requires ISE software version 10.1.03 or later.

(e.g. all configuration pins taken together) when operating in the User mode. This is accomplished by setting the *Persist* option to *Yes*.

Multiple FPGAs can be configured using the Slave Parallel mode and can be made to start-up simultaneously. Figure 27 shows the device connections. To configure multiple devices in this way, wire the individual CCLK, Data, RDWR_B, and BUSY pins of all the devices in parallel. The individual devices are loaded separately by deasserting the CS_B pin of each device in turn and writing the appropriate data.



Notes:

1. There are two ways to use the DONE line. First, one may set the BitGen option DriveDone to "Yes" only for the last FPGA to be configured in the chain shown above (or for the single FPGA as may be the case). This enables the DONE pin to drive High; thus, no pull-up resistor is necessary. DriveDone is set to "No" for the remaining FPGAs in the chain. Second, DriveDone can be set to "No" for all FPGAs. Then all DONE lines are open-drain and require the pull-up resistor shown in grey. In most cases, a value between 3.3KΩ to 4.7KΩ is sufficient. However, when using DONE synchronously with a long chain of FPGAs, cumulative capacitance may necessitate lower resistor values (e.g. down to 330Ω) in order to ensure a rise time within one clock cycle.
2. If the FPGAs use different configuration data files, configure them in sequence by first asserting the CS_B of one FPGA then asserting the CS_B of the other FPGA.
3. For information on how to program the FPGA using 3.3V signals and power, see 3.3V-Tolerant Configuration Interface.

Figure 27: **Connection Diagram for Slave Parallel Configuration**

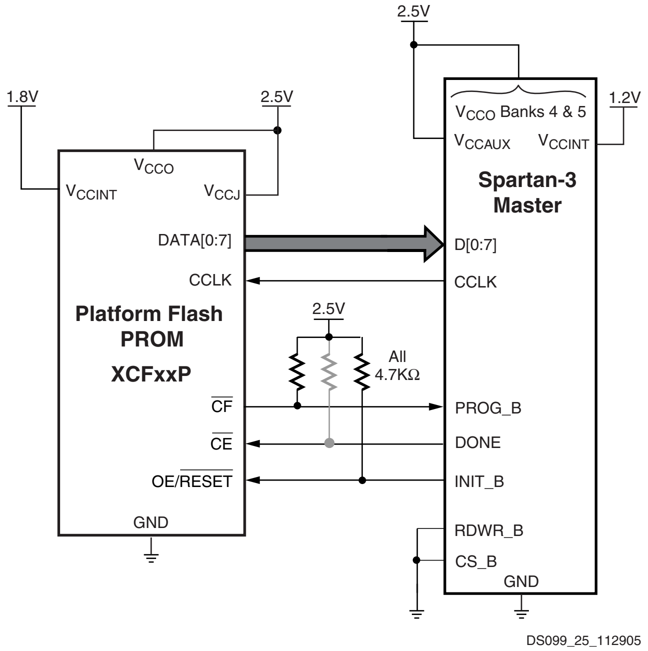


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Figure 28: **Connection Diagram for Master Parallel Configuration**

Master Parallel Mode

In this mode, the FPGA configures from byte-wide data, and the FPGA supplies the CCLK configuration clock. In Master configuration modes, CCLK behaves as a bidirectional I/O pin. Timing is similar to the Slave Parallel mode except that CCLK is supplied by the FPGA. The device connections are shown in Figure 28.

Boundary-Scan (JTAG) Mode

In Boundary-Scan mode, dedicated pins are used for configuring the FPGA. The configuration is done entirely through the IEEE 1149.1 Test Access Port (TAP). FPGA configuration using the Boundary-Scan mode is compatible with the IEEE Std 1149.1-1993 standard and IEEE Std 1532 for In-System Configurable (ISC) devices.

Configuration through the boundary-scan port is always available, regardless of the selected configuration mode. In some cases, however, the mode pin setting may affect proper programming of the device due to various interactions. For example, if the mode pins are set to Master Serial or Master Parallel mode, and the associated PROM is already programmed with a valid configuration image, then there is potential for configuration interference between the JTAG and PROM data. Selecting the Boundary-Scan mode disables the other modes and is the most reliable mode when programming via JTAG.

Configuration Sequence

The configuration of Spartan-3 devices is a three-stage process that occurs after Power-On Reset or the assertion of PROG_B. POR occurs after the V_{CCINT}, V_{CCAUX}, and V_{CCO} Bank 4 supplies have reached their respective maximum input threshold levels (see Table 29, page 59). After POR, the three-stage process begins.

First, the configuration memory is cleared. Next, configuration data is loaded into the memory, and finally, the logic is activated by a start-up process. A flow diagram for the configuration sequence of the Serial and Parallel modes is shown in Figure 29. The flow diagram for the Boundary-Scan configuration sequence appears in Figure 30.

Initial Spartan-3 FPGA mask revisions have a limit on how fast the V_{CCO} supply can ramp. The minimum allowed V_{CCO} ramp rate appears as T_{CCO} in Table 30, page 60. The minimum rate is affected by the package inductance. Consequently, the ball grid array and chip-scale packages (CP132, FT256, FG456, FG676, and FG900) allow a faster ramp rate than the quad-flat packages (VQ100, TQ144, and PQ208).

Configuration Data Retention, Brown-Out

The FPGA's configuration data is stored in robust CMOS configuration latches. The data in these latches is retained even when the voltages drop to the minimum levels necessary to preserve RAM contents. This is specified in Table 31, page 60.

If, after configuration, the V_{CCAUX} or V_{CCINT} supply drops below its data retention voltage, clear the current device configuration using one of the following methods:

- Force the V_{CCAUX} or V_{CCINT} supply voltage below the minimum Power On Reset (POR) voltage threshold Table 29, page 59).
- Assert PROG_B Low.

The POR circuit does not monitor the VCCO_4 supply after configuration. Consequently, dropping the VCCO_4 voltage does not reset the device by triggering a Power-On Reset (POR) event.

No Internal Charge Pumps or Free-Running Oscillators

Some system applications are sensitive to sources of analog noise. Spartan-3 FPGA circuitry is fully static and does not employ internal charge pumps.

The CCLK configuration clock is active during the FPGA configuration process. After configuration completes, the CCLK oscillator is automatically disabled unless the Bitstream Generator (BitGen) option ***Persist=Yes***. See Module 4: Table 80, page 125.

Spartan-3 FPGAs optionally support a featured called Digitally Controlled Impedance (DCI). When used in an application, the DCI logic uses an internal oscillator. The DCI logic is only enabled if the FPGA application specifies an I/O standard that requires DCI (LVDCI_33, LVDCI_25, etc.). If DCI is not used, the associated internal oscillator is also disabled.

In summary, unless an application uses the ***Persist=Yes*** option or specifies a DCI I/O standard, an FPGA with no external switching remains fully static.

Table 36: **DC Characteristics of User I/Os Using Single-Ended Standards**

Signal Standard (IOSTANDARD) and Current Drive Attribute (mA)		Test Conditions		Logic Level Characteristics	
		I_{OL} (mA)	I_{OH} (mA)	V_{OL} Max (V)	V_{OH} Min (V)
GTL		32	–	0.4	–
GTL_DCI		Note 3	Note 3		
GTLP		36	–	0.6	–
GTLP_DCI		Note 3	Note 3		
HSLVDCI_15		Note 3	Note 3	0.4	V_{CCO} – 0.4
HSLVDCI_18					
HSLVDCI_25					
HSLVDCI_33					
HSTL_I		8	–8	0.4	V_{CCO} – 0.4
HSTL_I_DCI		Note 3	Note 3		
HSTL_III		24	–8	0.4	V_{CCO} – 0.4
HSTL_III_DCI		Note 3	Note 3		
HSTL_I_18		8	–8	0.4	V_{CCO} – 0.4
HSTL_I_DCI_18		Note 3	Note 3		
HSTL_II_18		16	–16	0.4	V_{CCO} – 0.4
HSTL_II_DCI_18		Note 3	Note 3		
HSTL_III_18		24	–8	0.4	V_{CCO} – 0.4
HSTL_III_DCI_18		Note 3	Note 3		
LVCMOS12(4)	2	2	–2	0.4	V_{CCO} – 0.4
	4	4	–4		
	6	6	–6		
LVCMOS15(4)	2	2	–2	0.4	V_{CCO} – 0.4
	4	4	–4		
	6	6	–6		
	8	8	–8		
	12	12	–12		
LVDCI_15, LVDCI_DV2_15		Note 3	Note 3		
LVCMOS18(4)	2	2	–2	0.4	V_{CCO} – 0.4
	4	4	–4		
	6	6	–6		
	8	8	–8		
	12	12	–12		
	16	16	–16		
LVDCI_18, LVDCI_DV2_18		Note 3	Note 3		
LVCMOS25(4,5)	2	2	–2	0.4	V_{CCO} – 0.4
	4	4	–4		
	6	6	–6		
	8	8	–8		
	12	12	–12		
	16	16	–16		
	24	24	–24		
LVDCI_25, LVDCI_DV2_25		Note 3	Note 3		

Table 42: **Setup and Hold Times for the IOB Input Path *(Cont'd)***

Symbol	Description	Conditions	Device	Speed Grade -5 Min	Speed Grade -4 Min	Units
Hold Times						
T_{IOICKP}	Time from the active transition at the IFF's ICLK input to the point where data must be held at the Input pin. No Input Delay is programmed.	LVCMOS25[3], IOBDELAY = NONE	XC3S50	-0.55	-0.55	ns
			XC3S200	-0.29	-0.29	ns
			XC3S400	-0.29	-0.29	ns
			XC3S1000	-0.55	-0.55	ns
			XC3S1500	-0.55	-0.55	ns
			XC3S2000	-0.55	-0.55	ns
			XC3S4000	-0.61	-0.61	ns
			XC3S5000	-0.68	-0.68	ns
$T_{IOICKPD}$	Time from the active transition at the IFF's ICLK input to the point where data must be held at the Input pin. The Input Delay is programmed.	LVCMOS25[3], IOBDELAY = IFD	XC3S50	-2.74	-2.74	ns
			XC3S200	-3.00	-3.00	ns
			XC3S400	-2.90	-2.90	ns
			XC3S1000	-3.24	-3.24	ns
			XC3S1500	-3.55	-3.55	ns
			XC3S2000	-4.57	-4.57	ns
			XC3S4000	-4.96	-4.96	ns
			XC3S5000	-5.09	-5.09	ns
Set/Reset Pulse Width						
T_{RPW_IOB}	Minimum pulse width to SR control input on IOB		All	0.66	0.76	ns

Notes:

1. The numbers in this table are tested using the methodology presented in Table 48 and are based on the operating conditions set forth in Table 32 and Table 35.
2. This setup time requires adjustment whenever a signal standard other than LVCMOS25 is assigned to the data Input. If this is true, add the appropriate Input adjustment from Table 44.
3. These hold times require adjustment whenever a signal standard other than LVCMOS25 is assigned to the data Input. If this is true, subtract the appropriate Input adjustment from Table 44. When the hold time is negative, it is possible to change the data before the clock's active edge.

Table 44: **Input Timing Adjustments for IOB *(Cont'd)***

Convert Input Time from LVCMOS25 to the Following Signal Standard (IOSTANDARD)	Add the Adjustment Below		Units
	Speed Grade		
	-5	-4	
LVCMOS15	0.42	0.49	ns
LVDCI_15	0.38	0.43	ns
LVDCI_DV2_15	0.38	0.44	ns
LVCMOS18	0.24	0.28	ns
LVDCI_18	0.29	0.33	ns
LVDCI_DV2_18	0.28	0.33	ns
LVCMOS25	0	0	ns
LVDCI_25	0.05	0.05	ns
LVDCI_DV2_25	0.04	0.04	ns
LVCMOS33, LVDCI_33, LVDCI_DV2_33	–0.05	–0.02	ns
LVTTL	0.18	0.21	ns
PCI33_3	0.20	0.22	ns
SSTL18_I, SSTL18_I_DCI	0.39	0.45	ns
SSTL18_II	0.39	0.45	ns
SSTL2_I, SSTL2_I_DCI	0.40	0.46	ns
SSTL2_II, SSTL2_II_DCI	0.36	0.41	ns
Differential Standards			
LDT_25 (ULVDS_25)	0.76	0.88	ns
LVDS_25, LVDS_25_DCI	0.65	0.75	ns
BLVDS_25	0.34	0.39	ns
LVDSEXT_25, LVDSEXT_25_DCI	0.80	0.92	ns
LVPECL_25	0.18	0.21	ns
RSDS_25	0.43	0.50	ns
DIFF_HSTL_II_18, DIFF_HSTL_II_18_DCI	0.34	0.39	ns
DIFF_SSTL2_II, DIFF_SSTL2_II_DCI	0.65	0.75	ns

Notes:

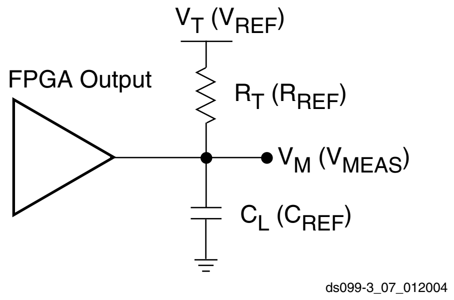
1. The numbers in this table are tested using the methodology presented in Table 48 and are based on the operating conditions set forth in Table 32, Table 35, and Table 37.
2. These adjustments are used to convert input path times originally specified for the LVCMOS25 standard to times that correspond to other signal standards.

Timing Measurement Methodology

When measuring timing parameters at the programmable I/Os, different signal standards call for different test conditions. Table 48 presents the conditions to use for each standard.

The method for measuring Input timing is as follows: A signal that swings between a Low logic level of V_L and a High logic level of V_H is applied to the Input under test. Some standards also require the application of a bias voltage to the V_{REF} pins of a given bank to properly set the input-switching threshold. The measurement point of the Input signal (V_M) is commonly located halfway between V_L and V_H.

The Output test setup is shown in Figure 35. A termination voltage V_T is applied to the termination resistor R_T, the other end of which is connected to the Output. For each standard, R_T and V_T generally take on the standard values recommended for minimizing signal reflections. If the standard does not ordinarily use terminations (e.g., LVCMOS, LVTTL), then R_T is set to 1MΩ to indicate an open connection, and V_T is set to zero. The same measurement point (V_M) that was used at the Input is also used at the Output.



Notes:

1. The names shown in parentheses are used in the IBIS file.

Figure 35: **Output Test Setup**

Table 48: **Test Methods for Timing Measurement at I/Os**

Signal Standard (IOSTANDARD)	Inputs			Outputs		Inputs and Outputs
	V_{REF} (V)	V_L (V)	V_H (V)	R_T (Ω)	V_T (V)	V_M (V)
Single-Ended						
GTL	0.8	$V_{REF} - 0.2$	$V_{REF} + 0.2$	25	1.2	V_{REF}
GTL_DCI				50	1.2	
GTLP	1.0	$V_{REF} - 0.2$	$V_{REF} + 0.2$	25	1.5	V_{REF}
GTLP_DCI				50	1.5	
HSLVDCI_15	0.9	$V_{REF} - 0.5$	$V_{REF} + 0.5$	1M	0	0.75
HSLVDCI_18						0.90
HSLVDCI_25						1.25
HSLVDCI_33						1.65
HSTL_I	0.75	$V_{REF} - 0.5$	$V_{REF} + 0.5$	50	0.75	V_{REF}
HSTL_I_DCI						
HSTL_III	0.90	$V_{REF} - 0.5$	$V_{REF} + 0.5$	50	1.5	V_{REF}
HSTL_III_DCI						
HSTL_I_18	0.90	$V_{REF} - 0.5$	$V_{REF} + 0.5$	50	0.9	V_{REF}
HSTL_I_DCI_18						
HSTL_II_18	0.90	$V_{REF} - 0.5$	$V_{REF} + 0.5$	50	0.9	V_{REF}
HSTL_II_DCI_18						

Table 59: **Switching Characteristics for the DLL *(Cont'd)***

Symbol	Description	Frequency Mode / FCLKIN Range	Device	Speed Grade				Units
				-5		-4		
				Min	Max	Min	Max	
Lock Time								
LOCK_DLL	When using the DLL alone: The time from deassertion at the DCM's Reset input to the rising transition at its LOCKED output. When the DCM is locked, the CLKIN and CLKFB signals are in phase	18 MHz ≤ F_{CLKIN} ≤ 30 MHz	All	–	2.88	–	2.88	ms
		30 MHz < F_{CLKIN} ≤ 40 MHz		–	2.16	–	2.16	ms
		40 MHz < F_{CLKIN} ≤ 50 MHz		–	1.20	–	1.20	ms
		50 MHz < F_{CLKIN} ≤ 60 MHz		–	0.60	–	0.60	ms
		F_{CLKIN} > 60 MHz		–	0.48	–	0.48	ms
Delay Lines								
DCM_TAP	Delay tap resolution	All	All	30.0	60.0	30.0	60.0	ps

Notes:

1. The numbers in this table are based on the operating conditions set forth in Table 32 and Table 58.
2. DLL specifications apply when any of the DLL outputs (CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, or CLKDV) are in use.
3. Only mask revision 'E' and later devices (see Mask and Fab Revisions, page 58) and all revisions of the XC3S50 and the XC3S1000 support DLL feedback using the CLK2X output. For all other Spartan-3 devices, use feedback from the CLK0 output (instead of the CLK2X output) and set the CLK_FEEDBACK attribute to 1X.
4. Indicates the maximum amount of output jitter that the DCM adds to the jitter on the CLKIN input.
5. This specification only applies if the attribute DUTY_CYCLE_CORRECTION = TRUE.

Digital Frequency Synthesizer (DFS)

Table 60: **Recommended Operating Conditions for the DFS**

Symbol		Description	Frequency Mode	Speed Grade				Units
				-5		-4		
				Min	Max	Min	Max	
Input Frequency Ranges[2]								
F_{CLKIN}	CLKIN_FREQ_FX	Frequency for the CLKIN input	All	1	280	1	280	MHz
Input Clock Jitter Tolerance[3]								
CLKIN_CYC_JITT_FX_LF		Cycle-to-cycle jitter at the CLKIN input	Low	–	±300	–	±300	ps
CLKIN_CYC_JITT_FX_HF			High	–	±150	–	±150	ps
CLKIN_PER_JITT_FX		Period jitter at the CLKIN input	All	–	±1	–	±1	ns

Notes:

1. DFS specifications apply when either of the DFS outputs (CLKFX or CLKFX180) are used.
2. If both DFS and DLL outputs are used on the same DCM, follow the more restrictive CLKIN_FREQ_DLL specifications in Table 58.
3. CLKIN input jitter beyond these limits may cause the DCM to lose lock.

Table 71: **Dual-Purpose Pins Used in Master or Slave Serial Mode**

Pin Name	Direction	Description
DIN	Input	**Serial Data Input:** During the Master or Slave Serial configuration modes, DIN is the serial configuration data input, and all data is synchronized to the rising CCLK edge. After configuration, this pin is available as a user I/O. This signal is located in Bank 4 and its output voltage determined by VCCO_4. The BitGen option ***Persist*** permits this pin to retain its configuration function in the User mode.
DOUT	Output	**Serial Data Output:** In a multi-FPGA design where all the FPGAs use serial mode, connect the DOUT output of one FPGA—in either Master or Slave Serial mode—to the DIN input of the next FPGA—in Slave Serial mode—so that configuration data passes from one to the next, in daisy-chain fashion. This “daisy chain” permits sequential configuration of multiple FPGAs. This signal is located in Bank 4 and its output voltage determined by VCCO_4. The BitGen option ***Persist*** permits this pin to retain its configuration function in the User mode.
INIT_B	Bidirectional (open-drain)	**Initializing Configuration Memory/Configuration Error:** Just after power is applied, the FPGA produces a Low-to-High transition on this pin indicating that initialization (*i.e.*, clearing) of the configuration memory has finished. Before entering the User mode, this pin functions as an open-drain output, which requires a pull-up resistor in order to produce a High logic level. In a multi-FPGA design, tie (wire AND) the INIT_B pins from all FPGAs together so that the common node transitions High only after all of the FPGAs have been successfully initialized. Externally holding this pin Low beyond the initialization phase delays the start of configuration. This action stalls the FPGA at the configuration step just before the mode select pins are sampled. During configuration, the FPGA indicates the occurrence of a data (i.e., CRC) error by asserting INIT_B Low. This signal is located in Bank 4 and its output voltage determined by VCCO_4. The BitGen option ***Persist*** permits this pin to retain its configuration function in the User mode.

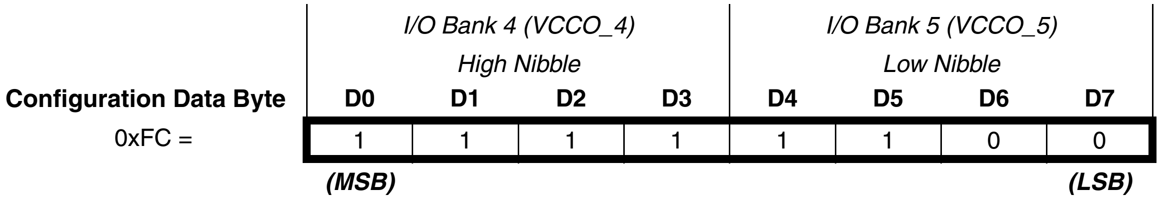


Figure 41: **Configuration Data Byte Mapping to D0-D7 Bits**

Parallel Configuration Modes (SelectMAP)

This section describes the dual-purpose configuration pins used during the Master and Slave Parallel configuration modes, sometimes also called the SelectMAP modes. In both Master and Slave Parallel configuration modes, D0-D7 form the byte-wide configuration data input. See Table 75 for Mode Select pin settings required for Parallel modes.

As shown in Figure 41, D0 is the most-significant bit while D7 is the least-significant bit. Bits D0-D3 form the high nibble of the byte and bits D4-D7 form the low nibble.

In the Parallel configuration modes, both the VCCO_4 and VCCO_5 voltage supplies are required and must both equal the voltage of the attached configuration device, typically either 2.5V or 3.3V.

Assert Low both the chip-select pin, CS_B, and the read/write control pin, RDWR_B, to write the configuration data byte presented on the D0-D7 pins to the FPGA on a rising-edge of the configuration clock, CCLK. The order of CS_B and RDWR_B does not matter, although RDWR_B must be asserted throughout the configuration process. If RDWR_B is de-asserted during configuration, the FPGA aborts the configuration operation.

After configuration, these pins are available as general-purpose user I/O. However, the SelectMAP configuration interface is optionally available for debugging and dynamic reconfiguration. To use these SelectMAP pins after configuration, set the Persist bitstream generation option.

The Readback debugging option, for example, requires the Persist bitstream generation option. During Readback mode, assert CS_B Low, along with RDWR_B High, to read a configuration data byte from the FPGA to the D0-D7 bus on a rising CCLK edge. During Readback mode, D0-D7 are output pins.

In all the cases, the configuration data and control signals are synchronized to the rising edge of the CCLK clock signal.

HSWAP_EN: Disable Pull-up Resistors During Configuration

As shown in Table 76, a Low on this asynchronous pin enables pull-up resistors on all user I/Os not actively involved in the configuration process, although only until device configuration completes. A High disables the pull-up resistors during configuration, which is the desired state for some applications.

The dedicated configuration CONFIG pins (CCLK, DONE, PROG_B, HSWAP_EN, M2, M1, M0), the JTAG pins (TDI, TMS, TCK, TDO) and the INIT_B always have active pull-up resistors during configuration, regardless of the value on HSWAP_EN.

After configuration, HSWAP_EN becomes a "don’t care" input and any pull-up resistors previously enabled by HSWAP_EN are disabled. If a user I/O in the application requires a pull-up resistor after configuration, place a PULLUP primitive on the associated I/O pin or, for some pins, set the associated bitstream generator option.

Table 76: **HSWAP_EN Encoding**

HSWAP_EN	Function
During Configuration	
0	Enable pull-up resistors on all pins not actively involved in the configuration process. Pull-ups are only active until configuration completes. See Table 79.
1	No pull-up resistors during configuration.
After Configuration, User Mode	
X	This pin has no function except during device configuration.

Notes:

1. X = don’t care, either 0 or 1.

The Bitstream generator option HswapenPin determines whether a pull-up resistor to VCCAUX, a pull-down resistor, or no resistor is present on HSWAP_EN after configuration.

JTAG: Dedicated JTAG Port Pins

Table 77: **JTAG Pin Descriptions**

Pin Name	Direction	Description	Bitstream Generation Option
TCK	Input	**Test Clock:** The TCK clock signal synchronizes all boundary scan operations on its rising edge.	The BitGen option **TckPin** determines whether a pull-up resistor, pull-down resistor or no resistor is present.
TDI	Input	**Test Data Input:** TDI is the serial data input for all JTAG instruction and data registers. This input is sampled on the rising edge of TCK.	The BitGen option **TdiPin** determines whether a pull-up resistor, pull-down resistor or no resistor is present.
TMS	Input	**Test Mode Select:** The TMS input controls the sequence of states through which the JTAG TAP state machine passes. This input is sampled on the rising edge of TCK.	The BitGen option **TmsPin** determines whether a pull-up resistor, pull-down resistor or no resistor is present.
TDO	Output	**Test Data Output:** The TDO pin is the data output for all JTAG instruction and data registers. This output is sampled on the rising edge of TCK. The TDO output is an active totem-pole driver and is not like the open-collector TDO output on Virtex®-II Pro FPGAs.	The BitGen option **TdoPin** determines whether a pull-up resistor, pull-down resistor or no resistor is present.

These pins are dedicated connections to the four-wire IEEE 1532/IEEE 1149.1 JTAG port, shown in Figure 43 and described in Table 77. The JTAG port is used for boundary-scan testing, device configuration, application debugging, and possibly an additional serial port for the application. These pins are dedicated and are not available as user-I/O pins. Every package has four dedicated JTAG pins and these pins are powered by the +2.5V VCCAUX supply.

For additional information on JTAG configuration, see Boundary-Scan (JTAG) Mode, page 50.

Table 86: **Spartan-3 FPGA Package Thermal Characteristics *(Cont'd)***

Package	Device	Junction-to-Case (θ_{JC})	Junction-to-Board (θ_{JB})	Junction-to-Ambient (θ_{JA}) at Different Air Flows				Units
				Still Air (0 LFM)	250 LFM	500 LFM	750 LFM	
FG(G)1156[(1)]	XC3S4000	1.9	–	14.7	11.4	10.1	9.0	°C/Watt
	XC3S5000	1.9	8.9	14.5	11.3	10.0	8.9	°C/Watt

Notes:

1. The CP132, CPG132, FG1156, and FGG1156 packages are discontinued. See http://www.xilinx.com/support/documentation/spartan-3_customer_notices.htm.

VQ100: 100-lead Very-Thin Quad Flat Package

The XC3S50 and the XC3S200 devices are available in the 100-lead very-thin quad flat package, VQ100. Both devices share a common footprint for this package as shown in Table 87 and Figure 44.

All the package pins appear in Table 87 and are sorted by bank number, then by pin name. Pairs of pins that form a differential I/O pair appear together in the table. The table also shows the pin number for each pin and the pin type, as defined earlier.

An electronic version of this package pinout table and footprint diagram is available for download from the Xilinx website at http://www.xilinx.com/support/documentation/data_ sheets/s3_pin.zip.

Pinout Table

Table 87: **VQ100 Package Pinout**

Bank	XC3S50 XC3S200 Pin Name	VQ100 Pin Number	Type
0	IO_L01N_0/VRP_0	P97	DCI
0	IO_L01P_0/VRN_0	P96	DCI
0	IO_L31N_0	P92	I/O
0	IO_L31P_0/VREF_0	P91	VREF
0	IO_L32N_0/GCLK7	P90	GCLK
0	IO_L32P_0/GCLK6	P89	GCLK
0	VCCO_0	P94	VCCO
1	IO	P81	I/O
1	IO_L01N_1/VRP_1	P80	DCI
1	IO_L01P_1/VRN_1	P79	DCI
1	IO_L31N_1/VREF_1	P86	VREF
1	IO_L31P_1	P85	I/O
1	IO_L32N_1/GCLK5	P88	GCLK
1	IO_L32P_1/GCLK4	P87	GCLK
1	VCCO_1	P83	VCCO
2	IO_L01N_2/VRP_2	P75	DCI
2	IO_L01P_2/VRN_2	P74	DCI
2	IO_L21N_2	P72	I/O
2	IO_L21P_2	P71	I/O
2	IO_L24N_2	P68	I/O
2	IO_L24P_2	P67	I/O

Table 91: **TQ144 Package Pinout *(Cont'd)***

Bank	XC3S50, XC3S200, XC3S400 Pin Name	TQ144 Pin Number	Type
5	IO_L32P_5/GCLK2	P52	GCLK
6	IO_L01N_6/VRP_6	P36	DCI
6	IO_L01P_6/VRN_6	P35	DCI
6	IO_L20N_6	P33	I/O
6	IO_L20P_6	P32	I/O
6	IO_L21N_6	P31	I/O
6	IO_L21P_6	P30	I/O
6	IO_L22N_6	P28	I/O
6	IO_L22P_6	P27	I/O
6	IO_L23N_6	P26	I/O
6	IO_L23P_6	P25	I/O
6	IO_L24N_6/VREF_6	P24	VREF
6	IO_L24P_6	P23	I/O
6	IO_L40N_6	P21	I/O
6	IO_L40P_6/VREF_6	P20	VREF
7	IO/VREF_7	P4	VREF
7	IO_L01N_7/VRP_7	P2	DCI
7	IO_L01P_7/VRN_7	P1	DCI
7	IO_L20N_7	P6	I/O
7	IO_L20P_7	P5	I/O
7	IO_L21N_7	P8	I/O
7	IO_L21P_7	P7	I/O
7	IO_L22N_7	P11	I/O
7	IO_L22P_7	P10	I/O
7	IO_L23N_7	P13	I/O
7	IO_L23P_7	P12	I/O
7	IO_L24N_7	P15	I/O
7	IO_L24P_7	P14	I/O
7	IO_L40N_7/VREF_7	P18	VREF
7	IO_L40P_7	P17	I/O
0,1	VCCO_TOP	P126	VCCO
0,1	VCCO_TOP	P138	VCCO
0,1	VCCO_TOP	P115	VCCO
2,3	VCCO_RIGHT	P106	VCCO
2,3	VCCO_RIGHT	P75	VCCO
2,3	VCCO_RIGHT	P91	VCCO
4,5	VCCO_BOTTOM	P54	VCCO
4,5	VCCO_BOTTOM	P43	VCCO
4,5	VCCO_BOTTOM	P66	VCCO
6,7	VCCO_LEFT	P19	VCCO

Table 98: **FG320 Package Pinout *(Cont'd)***

Bank	XC3S400, XC3S1000, XC3S1500 Pin Name	FG320 Pin Number	Type
7	IO_L20P_7	E1	I/O
7	IO_L21N_7	E4	I/O
7	IO_L21P_7	F4	I/O
7	IO_L22N_7	G5	I/O
7	IO_L22P_7	F5	I/O
7	IO_L23N_7	G1	I/O
7	IO_L23P_7	F2	I/O
7	IO_L24N_7	G4	I/O
7	IO_L24P_7	G3	I/O
7	IO_L27N_7	H5	I/O
7	IO_L27P_7/VREF_7	H6	VREF
7	IO_L34N_7	H4	I/O
7	IO_L34P_7	H3	I/O
7	IO_L35N_7	H1	I/O
7	IO_L35P_7	H2	I/O
7	IO_L39N_7	J1	I/O
7	IO_L39P_7	J2	I/O
7	IO_L40N_7/VREF_7	J5	VREF
7	IO_L40P_7	J4	I/O
7	VCCO_7	F3	VCCO
7	VCCO_7	H7	VCCO
7	VCCO_7	J7	VCCO
N/A	GND	A1	GND
N/A	GND	A13	GND
N/A	GND	A18	GND
N/A	GND	A6	GND
N/A	GND	B17	GND
N/A	GND	B2	GND
N/A	GND	C10	GND
N/A	GND	C9	GND
N/A	GND	F1	GND
N/A	GND	F18	GND
N/A	GND	G12	GND
N/A	GND	G7	GND
N/A	GND	H10	GND
N/A	GND	H11	GND
N/A	GND	H8	GND
N/A	GND	H9	GND
N/A	GND	J11	GND
N/A	GND	J16	GND

Table 103: **FG676 Package Pinout *(Cont'd)***

Bank	XC3S1000 Pin Name	XC3S1500 Pin Name	XC3S2000 Pin Name	XC3S4000 Pin Name	XC3S5000 Pin Name	FG676 Pin Number	Type
6	IO_L20N_6	IO_L20N_6	IO_L20N_6	IO_L20N_6	IO_L20N_6	V7	I/O
6	IO_L20P_6	IO_L20P_6	IO_L20P_6	IO_L20P_6	IO_L20P_6	U7	I/O
6	IO_L21N_6	IO_L21N_6	IO_L21N_6	IO_L21N_6	IO_L21N_6	V5	I/O
6	IO_L21P_6	IO_L21P_6	IO_L21P_6	IO_L21P_6	IO_L21P_6	V4	I/O
6	IO_L22N_6	IO_L22N_6	IO_L22N_6	IO_L22N_6	IO_L22N_6	V3	I/O
6	IO_L22P_6	IO_L22P_6	IO_L22P_6	IO_L22P_6	IO_L22P_6	V2	I/O
6	IO_L23N_6	IO_L23N_6	IO_L23N_6	IO_L23N_6	IO_L23N_6	U6	I/O
6	IO_L23P_6	IO_L23P_6	IO_L23P_6	IO_L23P_6	IO_L23P_6	U5	I/O
6	IO_L24N_6/VREF_6	IO_L24N_6/VREF_6	IO_L24N_6/VREF_6	IO_L24N_6/VREF_6	IO_L24N_6/VREF_6	U4	VREF
6	IO_L24P_6	IO_L24P_6	IO_L24P_6	IO_L24P_6	IO_L24P_6	U3	I/O
6	IO_L26N_6	IO_L26N_6	IO_L26N_6	IO_L26N_6	IO_L26N_6	U2	I/O
6	IO_L26P_6	IO_L26P_6	IO_L26P_6	IO_L26P_6	IO_L26P_6	U1	I/O
6	IO_L27N_6	IO_L27N_6	IO_L27N_6	IO_L27N_6	IO_L27N_6	T8	I/O
6	IO_L27P_6	IO_L27P_6	IO_L27P_6	IO_L27P_6	IO_L27P_6	T7	I/O
6	IO_L28N_6	IO_L28N_6	IO_L28N_6	IO_L28N_6	IO_L28N_6	T6	I/O
6	IO_L28P_6	IO_L28P_6	IO_L28P_6	IO_L28P_6	IO_L28P_6	T5	I/O
6	IO_L29N_6	IO_L29N_6	IO_L29N_6	IO_L29N_6	IO_L29N_6	T2	I/O
6	IO_L29P_6	IO_L29P_6	IO_L29P_6	IO_L29P_6	IO_L29P_6	T1	I/O
6	IO_L31N_6	IO_L31N_6	IO_L31N_6	IO_L31N_6	IO_L31N_6	R8	I/O
6	IO_L31P_6	IO_L31P_6	IO_L31P_6	IO_L31P_6	IO_L31P_6	R7	I/O
6	IO_L32N_6	IO_L32N_6	IO_L32N_6	IO_L32N_6	IO_L32N_6	R6	I/O
6	IO_L32P_6	IO_L32P_6	IO_L32P_6	IO_L32P_6	IO_L32P_6	R5	I/O
6	IO_L33N_6	IO_L33N_6	IO_L33N_6	IO_L33N_6	IO_L33N_6	T4	I/O
6	IO_L33P_6	IO_L33P_6	IO_L33P_6	IO_L33P_6	IO_L33P_6	R3	I/O
6	IO_L34N_6/VREF_6	IO_L34N_6/VREF_6	IO_L34N_6/VREF_6	IO_L34N_6/VREF_6	IO_L34N_6/VREF_6	R2	VREF
6	IO_L34P_6	IO_L34P_6	IO_L34P_6	IO_L34P_6	IO_L34P_6	R1	I/O
6	IO_L35N_6	IO_L35N_6	IO_L35N_6	IO_L35N_6	IO_L35N_6	P8	I/O
6	IO_L35P_6	IO_L35P_6	IO_L35P_6	IO_L35P_6	IO_L35P_6	P7	I/O
6	IO_L38N_6	IO_L38N_6	IO_L38N_6	IO_L38N_6	IO_L38N_6	P6	I/O
6	IO_L38P_6	IO_L38P_6	IO_L38P_6	IO_L38P_6	IO_L38P_6	P5	I/O
6	IO_L39N_6	IO_L39N_6	IO_L39N_6	IO_L39N_6	IO_L39N_6	P4	I/O
6	IO_L39P_6	IO_L39P_6	IO_L39P_6	IO_L39P_6	IO_L39P_6	P3	I/O
6	IO_L40N_6	IO_L40N_6	IO_L40N_6	IO_L40N_6	IO_L40N_6	P2	I/O
6	IO_L40P_6/VREF_6	IO_L40P_6/VREF_6	IO_L40P_6/VREF_6	IO_L40P_6/VREF_6	IO_L40P_6/VREF_6	P1	VREF
6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	P9	VCCO
6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	P10	VCCO
6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	R9	VCCO
6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	T3	VCCO
6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	T9	VCCO
6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	U8	VCCO
6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	V8	VCCO
6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	VCCO_6	Y3	VCCO
7	IO_L01N_7/VRP_7	IO_L01N_7/VRP_7	IO_L01N_7/VRP_7	IO_L01N_7/VRP_7	IO_L01N_7/VRP_7	F5	DCI

Table 110: **FG1156 Package Pinout *(Cont'd)***

Bank	XC3S4000 Pin Name	XC3S5000 Pin Name	FG1156 Pin Number	Type
6	IO_L16N_6	IO_L16N_6	AE2	I/O
6	IO_L16P_6	IO_L16P_6	AE1	I/O
6	IO_L17N_6	IO_L17N_6	AD10	I/O
6	IO_L17P_6/VREF_6	IO_L17P_6/VREF_6	AD9	VREF
6	IO_L19N_6	IO_L19N_6	AD2	I/O
6	IO_L19P_6	IO_L19P_6	AD1	I/O
6	IO_L20N_6	IO_L20N_6	AC11	I/O
6	IO_L20P_6	IO_L20P_6	AC10	I/O
6	IO_L21N_6	IO_L21N_6	AC8	I/O
6	IO_L21P_6	IO_L21P_6	AC7	I/O
6	IO_L22N_6	IO_L22N_6	AC6	I/O
6	IO_L22P_6	IO_L22P_6	AC5	I/O
6	IO_L23N_6	IO_L23N_6	AC2	I/O
6	IO_L23P_6	IO_L23P_6	AC1	I/O
6	IO_L24N_6/VREF_6	IO_L24N_6/VREF_6	AC9	VREF
6	IO_L24P_6	IO_L24P_6	AB10	I/O
6	IO_L25N_6	IO_L25N_6	AB8	I/O
6	IO_L25P_6	IO_L25P_6	AB7	I/O
6	IO_L26N_6	IO_L26N_6	AB4	I/O
6	IO_L26P_6	IO_L26P_6	AB3	I/O
6	IO_L27N_6	IO_L27N_6	AB11	I/O
6	IO_L27P_6	IO_L27P_6	AA11	I/O
6	IO_L28N_6	IO_L28N_6	AA8	I/O
6	IO_L28P_6	IO_L28P_6	AA7	I/O
6	IO_L29N_6	IO_L29N_6	AA6	I/O
6	IO_L29P_6	IO_L29P_6	AA5	I/O
6	IO_L30N_6	IO_L30N_6	AA4	I/O
6	IO_L30P_6	IO_L30P_6	AA3	I/O
6	IO_L31N_6	IO_L31N_6	AA2	I/O
6	IO_L31P_6	IO_L31P_6	AA1	I/O
6	IO_L32N_6	IO_L32N_6	Y11	I/O
6	IO_L32P_6	IO_L32P_6	Y10	I/O
6	IO_L33N_6	IO_L33N_6	Y4	I/O
6	IO_L33P_6	IO_L33P_6	Y3	I/O
6	IO_L34N_6/VREF_6	IO_L34N_6/VREF_6	Y2	VREF
6	IO_L34P_6	IO_L34P_6	Y1	I/O
6	IO_L35N_6	IO_L35N_6	Y9	I/O
6	IO_L35P_6	IO_L35P_6	W10	I/O
6	IO_L36N_6	IO_L36N_6	W7	I/O
6	IO_L36P_6	IO_L36P_6	W6	I/O

Date	Version	Description
11/30/07	2.3	Added XC3S5000 FG(G)676 package. Noted that the FG(G)1156 package is being discontinued. Updated Table 86 with latest thermal characteristics data.
06/25/08	2.4	Updated formatting and links.
12/04/09	2.5	Added link to UG332 in CCLK: Configuration Clock. Noted that the CP132, CPG132, FG1156, and FGG1156 packages are being discontinued in Table 81, Table 83, Table 84, Table 85, and Table 86. Updated CP132: 132-Ball Chip-Scale Package to indicate that the CP132 and CPG132 packages are being discontinued.
10/29/12	3.0	Added Notice of Disclaimer. Per XCN07022, updated the FG1156 and FGG1156 package discussion throughout document including in Table 81, Table 83, Table 84, Table 85, and Table 86. Per XCN08011, updated CP132 and CPG132 package discussion throughout document including in Table 81, Table 83, Table 84, Table 85, and Table 86. This product is not recommended for new designs.

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